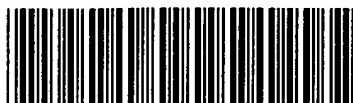


Search Notes

Application/Control No.

10/644,065

Examiner

David Q. Nguyen

Applicant(s)/Patent under
Reexamination

TAKAE ET AL.

Art Unit

2617

SEARCHED

Class	Subclass	Date	Examiner
455	558	9/14/2006	DN
455	406	9/14/2006	DN
455	407	9/14/2006	DN
455	410	9/14/2006	DN
455	411	9/14/2006	DN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
PGPUB text search-see interference search printout		9/14/2006	DN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East- see search printout	9/14/2006	DN
East-see interference search printout	9/14/2006	DN